DATA SHEET

74AHC2G00; 74AHCT2G00
2-input NAND gate

Product specification

2004 Jan 21

Philips
Semiconductors

PHILIPS

2-input NAND gate 74AHC2G00; 74AHCT2G00

FEATURES

- Symmetrical output impedance
- High noise immunity
- ESD protection:
  - HBM EIA/JESD22-A114-A exceeds 2000 V
  - MM EIA/JESD22-A115-A exceeds 200 V
  - CDM EIA/JESD22-C101 exceeds 500 V.
- Low power dissipation
- Balanced propagation delays
- SOT505-2 and SOT765-1 package
- Specified from –40 to +85 °C and –40 to +125 °C.

DESCRIPTION

The 74AHC2G/AHCT2G00 is a high-speed Si-gate CMOS device.

The 74AHC2G/AHCT2G00 provides the 2-input NAND gate function.

QUICK REFERENCE DATA

GND = 0 V; T_{amb} = 25 °C; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL		UNIT
			AHC2G	AHCT2G	
t_{PHL}/t_{PLH}	propagation delay nA and nB to nY	C_L = 15 pF; V_{CC} = 5 V	3.5	3.6	ns
C_I	input capacitance		1.5	1.5	pF
C_{PD}	power dissipation capacitance per gate	C_L = 50 pF; f = 1 MHz; notes 1 and 2	17	18	pF

Notes

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW).
   $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
   f_i = input frequency in MHz;
   f_o = output frequency in MHz;
   C_L = output load capacitance in pF;
   V_{CC} = supply voltage in Volts;
   N = total load switching outputs;
   $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.
2. The condition is V_I = GND to V_{CC}.

FUNCTION TABLE

See note 1.

INPUT		OUTPUT
nA	nB	nY
L	L	H
L	H	H
H	L	H
H	H	L

Note

1. H = HIGH voltage level;
   L = LOW voltage level.

ORDERING INFORMATION

TYPE NUMBER	PACKAGE					
	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE	MARKING
74AHC2G00DP	–40 to +125 °C	8	TSSOP8	plastic	SOT505-2	A00
74AHCT2G00DP	–40 to +125 °C	8	TSSOP8	plastic	SOT505-2	C00
74AHC2G00DC	–40 to +125 °C	8	VSSOP8	plastic	SOT765-1	A00
74AHCT2G00DC	–40 to +125 °C	8	VSSOP8	plastic	SOT765-1	C00

PINNING

PIN	SYMBOL	DESCRIPTION
1	1A	data input
2	1B	data input
3	2Y	data output
4	GND	ground (0 V)
5	2A	data input
6	2B	data input
7	1Y	data output
8	V_{CC}	supply voltage

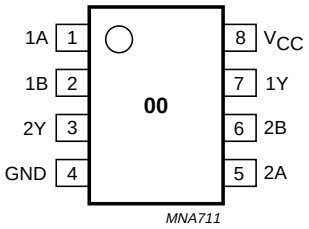


Fig.1 Pin configuration.

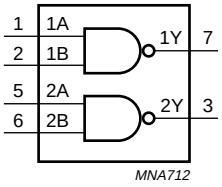


Fig.2 Logic symbol.

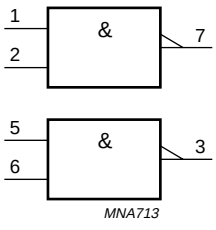


Fig.3 IEC logic symbol.

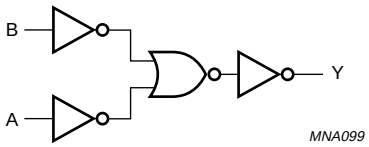


Fig.4 Logic diagram.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	74AHC2G00			74AHCT2G00			UNIT
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
V_{CC}	supply voltage		2.0	5.0	5.5	4.5	5.0	5.5	V
V_I	input voltage		0	–	5.5	0	–	5.5	V
V_O	output voltage		0	–	V_{CC}	0	–	V_{CC}	V
T_{amb}	operating ambient temperature	see DC and AC characteristics per device	–40	+25	+125	–40	+25	+125	°C
t_r, t_f	input rise and fall times	V_{CC} = 3.3 ± 0.3 V	–	–	100	–	–	–	ns/V
		V_{CC} = 5 ± 0.5 V	–	–	20	–	–	20	ns/V

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CC}	supply voltage		–0.5	+7.0	V
V_I	input voltage		–0.5	+7.0	V
I_{IK}	input diode current	V_I < –0.5 V	–	–20	mA
I_{OK}	output diode current	V_O < –0.5 V or V_O > V_{CC} + 0.5 V; note 1	–	±20	mA
I_O	output source or sink current	–0.5 V < V_O < V_{CC} + 0.5 V	–	±25	mA
I_{CC}, I_{GND}	V_{CC} or GND current		–	±75	mA
T_{stg}	storage temperature		–65	+150	°C
P_D	power dissipation	T_{amb} = –40 to +125 °C	–	250	mW

Note

1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

DC CHARACTERISTICS

Type 74AHC2G00

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = 25 °C							
V_{IH}	HIGH-level input voltage		2.0	1.5	–	–	V
			3.0	2.1	–	–	V
			5.5	3.85	–	–	V
V_{IL}	LOW-level input voltage		2.0	–	–	0.5	V
			3.0	–	–	0.9	V
			5.5	–	–	1.65	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	2.0	1.9	2.0	–	V
		I_O = –50 μA	3.0	2.9	3.0	–	V
		I_O = –50 μA	4.5	4.4	4.5	–	V
		I_O = –4.0 mA	3.0	2.58	–	–	V
		I_O = –8.0 mA	4.5	3.94	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	2.0	–	0	0.1	V
		I_O = 50 μA	3.0	–	0	0.1	V
		I_O = 50 μA	4.5	–	0	0.1	V
		I_O = 4.0 mA	3.0	–	–	0.36	V
		I_O = 8.0 mA	4.5	–	–	0.36	V
I_{LI}	input leakage current	V_I = V_{CC} or GND	5.5	–	–	0.1	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	10	μA
C_I	input capacitance		–	–	1.5	10	pF

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = −40 to +85 °C							
V_{IH}	HIGH-level input voltage		2.0	1.5	–	–	V
			3.0	2.1	–	–	V
			5.5	3.85	–	–	V
V_{IL}	LOW-level input voltage		2.0	–	–	0.5	V
			3.0	–	–	0.9	V
			5.5	–	–	1.65	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	2.0	1.9	–	–	V
		I_O = –50 μA	3.0	2.9	–	–	V
		I_O = –50 μA	4.5	4.4	–	–	V
		I_O = –4.0 mA	3.0	2.48	–	–	V
		I_O = –8.0 mA	4.5	3.8	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	2.0	–	–	0.1	V
		I_O = 50 μA	3.0	–	–	0.1	V
		I_O = 50 μA	4.5	–	–	0.1	V
		I_O = 4.0 mA	3.0	–	–	0.44	V
		I_O = 8.0 mA	4.5	–	–	0.44	V
I_{LI}	input leakage current	V_I = V_{CC} or GND	5.5	–	–	1.0	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	10	μA
C_I	input capacitance		–	–	–	10	pF

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = −40 to +125 °C							
V_{IH}	HIGH-level input voltage		2.0	1.5	–	–	V
			3.0	2.1	–	–	V
			5.5	3.85	–	–	V
V_{IL}	LOW-level input voltage		2.0	–	–	0.5	V
			3.0	–	–	0.9	V
			5.5	–	–	1.65	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	2.0	1.9	–	–	V
		I_O = –50 μA	3.0	2.9	–	–	V
		I_O = –50 μA	4.5	4.4	–	–	V
		I_O = –4.0 mA	3.0	2.40	–	–	V
		I_O = –8.0 mA	4.5	3.70	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	2.0	–	–	0.1	V
		I_O = 50 μA	3.0	–	–	0.1	V
		I_O = 50 μA	4.5	–	–	0.1	V
		I_O = 4.0 mA	3.0	–	–	0.55	V
		I_O = 8.0 mA	4.5	–	–	0.55	V
I_{LI}	input leakage current	V_I = V_{CC} or GND	5.5	–	–	2.0	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	40	μA
C_I	input capacitance		–	–	–	10	pF

Type 74AHCT2G00

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = 25 °C							
V_{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	–	–	V
V_{IL}	LOW-level input voltage		4.5 to 5.5	–	–	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	4.5	4.4	4.5	–	V
		I_O = –8.0 mA	4.5	3.94	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	4.5	–	0	0.1	V
		I_O = 8.0 mA	4.5	–	–	0.36	V
I_{LI}	input leakage current	V_I = V_{IH} or V_{IL}	5.5	–	–	0.1	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	1.0	μA
ΔI_{CC}	additional quiescent supply current per input pin	V_I = 3.4 V; other inputs at V_{CC} or GND; I_O = 0	5.5	–	–	1.35	mA
C_I	input capacitance			–	1.5	10	pF
T_{amb} = –40 to +85 °C							
V_{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	–	–	V
V_{IL}	LOW-level input voltage		4.5 to 5.5	–	–	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	4.5	4.4	–	–	V
		I_O = –8.0 mA	4.5	3.8	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	4.5	–	–	0.1	V
		I_O = 8.0 mA	4.5	–	–	0.44	V
I_{LI}	input leakage current	V_I = V_{IH} or V_{IL}	5.5	–	–	1.0	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	10	μA
ΔI_{CC}	additional quiescent supply current per input pin	V_I = 3.4 V; other inputs at V_{CC} or GND; I_O = 0	5.5	–	–	1.5	mA
C_I	input capacitance		–	–	–	10	pF

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = −40 to +125 °C							
V_{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	–	–	V
V_{IL}	LOW-level input voltage		4.5 to 5.5	–	–	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = –50 μA	4.5	4.4	–	–	V
		I_O = –8.0 mA	4.5	3.70	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 50 μA	4.5	–	–	0.1	V
		I_O = 8.0 mA	4.5	–	–	0.55	V
I_{LI}	input leakage current	V_I = V_{IH} or V_{IL}	5.5	–	–	2.0	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	5.5	–	–	40	μA
ΔI_{CC}	additional quiescent supply current per input pin	V_I = 3.4 V; other inputs at V_{CC} or GND; I_O = 0	5.5	–	–	1.5	mA
C_I	input capacitance		–	–	–	10	pF

AC CHARACTERISTICS

Type 74AHC2G00

GND = 0 V; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS			MIN.	TYP.	MAX.	UNIT
		WAVEFORMS	C_L (pF)	V_{CC} (V)				
T_{amb} = 25 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	3.0 to 3.6	–	4.5[1]	7.9	ns
				4.5 to 5.5	–	3.5[2]	5.5	ns
			50	3.0 to 3.6	–	6.5[1]	11.4	ns
				4.5 to 5.5	–	4.9[2]	7.5	ns
T_{amb} = −40 to +85 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	3.0 to 3.6	1.0	–	9.5	ns
				4.5 to 5.5	1.0	–	6.5	ns
			50	3.0 to 3.6	1.0	–	13.0	ns
				4.5 to 5.5	1.0	–	8.5	ns
T_{amb} = −40 to +125 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	3.0 to 3.6	1.0	–	10.5	ns
				4.5 to 5.5	1.0	–	7.0	ns
			50	3.0 to 3.6	1.0	–	14.5	ns
				4.5 to 5.5	1.0	–	9.5	ns

Notes

1. Typical values are measured at VCC = 3.3 V.
2. Typical values are measured at VCC = 5.0 V.

Type 74AHCT2G00

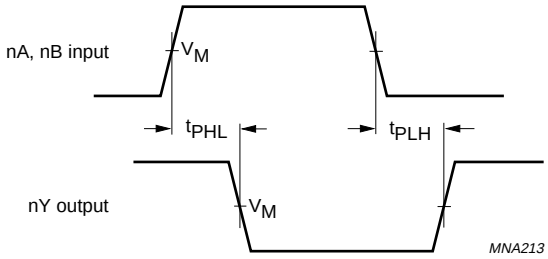
GND = 0 V; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS			MIN.	TYP.	MAX.	UNIT
		WAVEFORMS	C_L (pF)	V_{CC} (V)				
T_{amb} = 25 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	4.5 to 5.5	1.0	3.6[1]	6.2	ns
			50	4.5 to 5.5	1.0	5.0[1]	7.9	ns
T_{amb} = −40 to +85 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	4.5 to 5.5	1.0	–	7.1	ns
			50	4.5 to 5.5	1.0	–	9.0	ns
T_{amb} = −40 to +125 °C								
t_{PHL}/t_{PLH}	propagation delay input nA and nB to output nY	see Figs 5 and 6	15	4.5 to 5.5	1.0	–	8.0	ns
			50	4.5 to 5.5	1.0	–	10.0	ns

Note

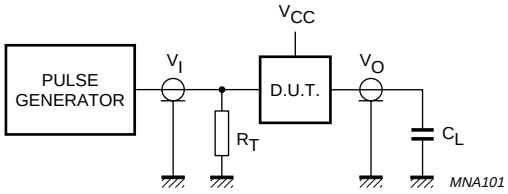
1. Typical values are measured at VCC = 5.0 V.

AC WAVEFORMS



FAMILY	V_M INPUT	V_M OUTPUT
AHC2G00	50% V_{CC}	50% V_{CC}
AHCT2G00	1.5 V	50% V_{CC}

Fig.5 The inputs (nA and nB) to output (nY) propagation delays.



FAMILY	V_I INPUT REQUIREMENTS
AHC2G00	GND to V_{CC}
AHCT2G00	GND to 3.0 V

Definitions for test circuit:

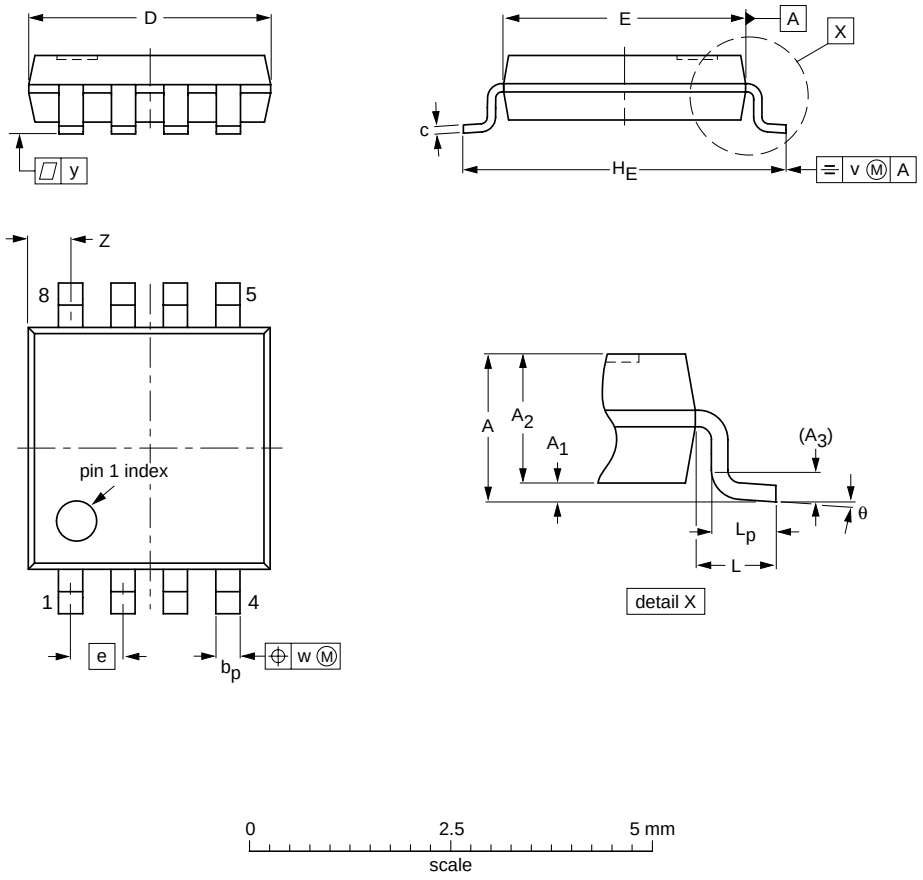
C_L = Load capacitance including jig and probe capacitance (See “AC characteristics” for the value).

R_T = Termination resistance should be equal to the output impedance Z_0 of the pulse generator.

Fig.6 Load circuitry for switching times.

PACKAGE OUTLINES

TSSOP8: plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm SOT505-2



DIMENSIONS (mm are the original dimensions)

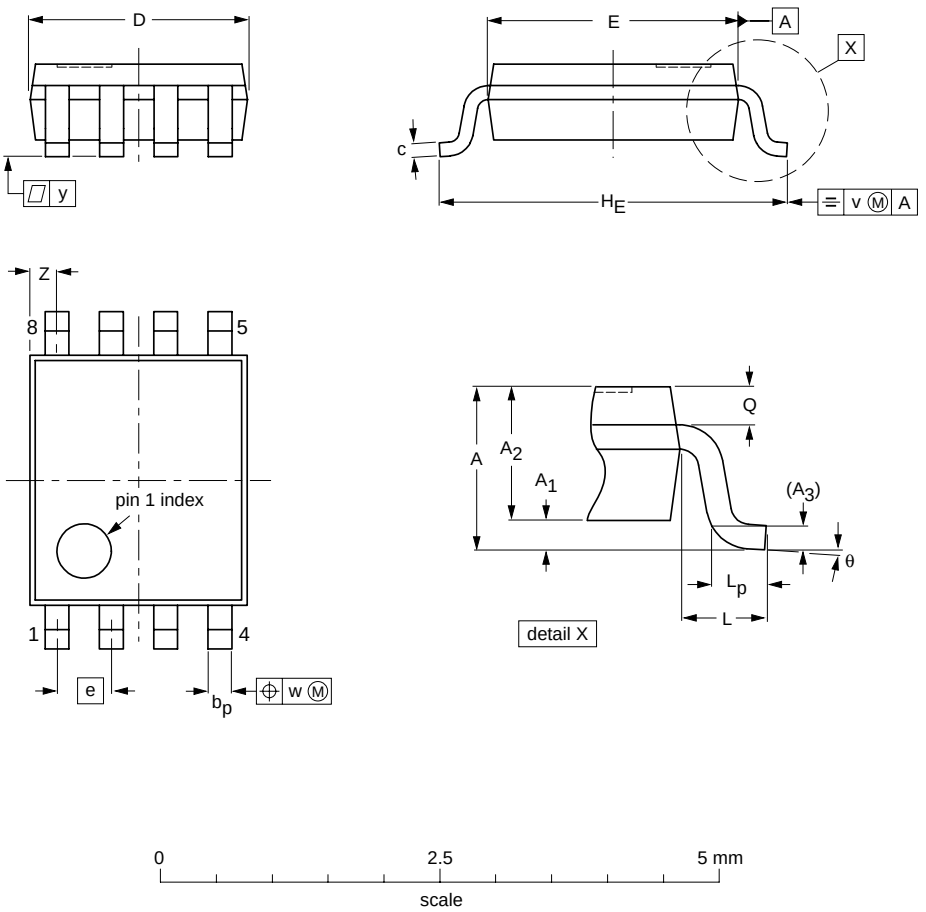
UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(1)}$	e	H_E	L	L_p	v	w	y	$Z^{(1)}$	θ
mm	1.1	0.15 0.00	0.95 0.75	0.25	0.38 0.22	0.18 0.08	3.1 2.9	3.1 2.9	0.65	4.1 3.9	0.5	0.47 0.33	0.2	0.13	0.1	0.70 0.35	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT505-2		- - -				02-01-16

VSSOP8: plastic very thin shrink small outline package; 8 leads; body width 2.3 mm **SOT765-1**



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(2)}$	e	H_E	L	L_p	Q	v	w	y	$Z^{(1)}$	θ
mm	1	0.15 0.00	0.85 0.60	0.12	0.27 0.17	0.23 0.08	2.1 1.9	2.4 2.2	0.5	3.2 3.0	0.4	0.40 0.15	0.21 0.19	0.2	0.13	0.1	0.4 0.1	8° 0°

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT765-1		MO-187				02-06-07

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS(1)	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

Notes

1. Please consult the most recently issued data sheet before initiating or completing a design.
2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

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